

SM3319NSQG-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Тур.)			
30	0.021 at V _{GS} = 10 V	18	3.8 nC			
	0.025 at V _{GS} = 4.5 V	17	3.6 110			

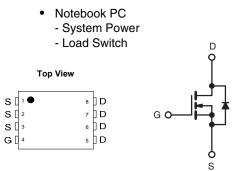
DFN 3x3 EP



FEATURES

- Halogen-free According to IEC 61249-2-21
- Trench Power MOSFET
- 100 % R_q Tested

APPLICATIONS



N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	30	V		
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		18 ^a		
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C		11 ^a		
	T _A = 25 °C	I _D	9 ^{b, c}		
	T _A = 70 °C		7 ^{b, c}	А	
Pulsed Drain Current		I _{DM}	35	A	
Continuous Source-Drain Diode Current	T _C = 25 °C		12 ^a		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.7 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	5		
Single Pulse Avalanche Energy		E _{AS}	1.25	mJ	
	T _C = 25 °C		15.6		
Maximum Dawar Dissinction	T _C = 70 °C	P _D	10	w	
Maximum Power Dissipation	T _A = 25 °C	FD FD	3.2 ^{b, c}	vv	
	T _A = 70 °C		2 ^{b, c}		
Operating Junction and Storage Temperatur	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Temper		260			

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	32	39	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	6.5	8	°C/W		

Notes:

a. Package Limited.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 81 °C/W.

e. The DFN 3X 3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

COMPLIANT

SPECIFICATIONS $T_J = 25 \text{ °C},$				1 -	1	1
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	1 1			1		1
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		- mV/°0
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 4.5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.0		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0$ V, $V_{GS} = \pm 20$ V			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μΑ
Zero Gale Voltage Drain Gurrent	'DSS	V_{DS} = 30 V, V_{GS} = 0 V, T_{J} = 55 $^{\circ}\text{C}$			5	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5$ V, V_{GS} = 10 V	20			Α
	Р	V _{GS} = 10 V, I _D = 7.8 A		0.021		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 7.0 \text{ A}$		0.025		
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 7.8 \text{ A}$		17		S
Dynamic ^b			Ι		•	
Input Capacitance	C _{iss}			435		pF
Output Capacitance	C _{oss}	V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz		95		
Reverse Transfer Capacitance	C _{rss}			42		
T + 1 0 + 01	0	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 7.8 \text{ A}$		8	12	nC
Total Gate Charge	Qg			3.8	6	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 7.8 A		1.4		
Gate-Drain Charge	Q _{gd}			1.1		
Gate Resistance	Rg	f = 1 MHz	1.5	3.2	4.5	Ω
Turn-On Delay Time	t _{d(on)}			15	25	-
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_{1} = 2.4 \Omega$		12	20	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 6.3 \text{ A}, V_{GEN} = 4.5 \text{ V}, \text{ R}_g = 1 \Omega$		13	20	
Fall Time	t _f	-		10	15	
Turn-On Delay Time	t _{d(on)}			5	10	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 2.4 Ω		10	15	-
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 6.3 \text{ A}, V_{GEN} = 10 \text{ V}, \text{ R}_q = 1 \Omega$		15	25	
Fall Time	t _f	Č.		10	15	
Drain-Source Body Diode Characteristic				I	I	1
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C		12		Ι.
Pulse Diode Forward Current	I _{SM}				35	A
Body Diode Voltage	V _{SD}	$I_{\rm S} = 6.3$ A, $V_{\rm GS} = 0$ V		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			15	25	ns
Body Diode Reverse Recovery Charge	Q _{rr}			7	12	nC
Reverse Recovery Fall Time	t _a	$I_F = 6.3 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		9		
Reverse Recovery Rise Time	t _b			6		ns

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

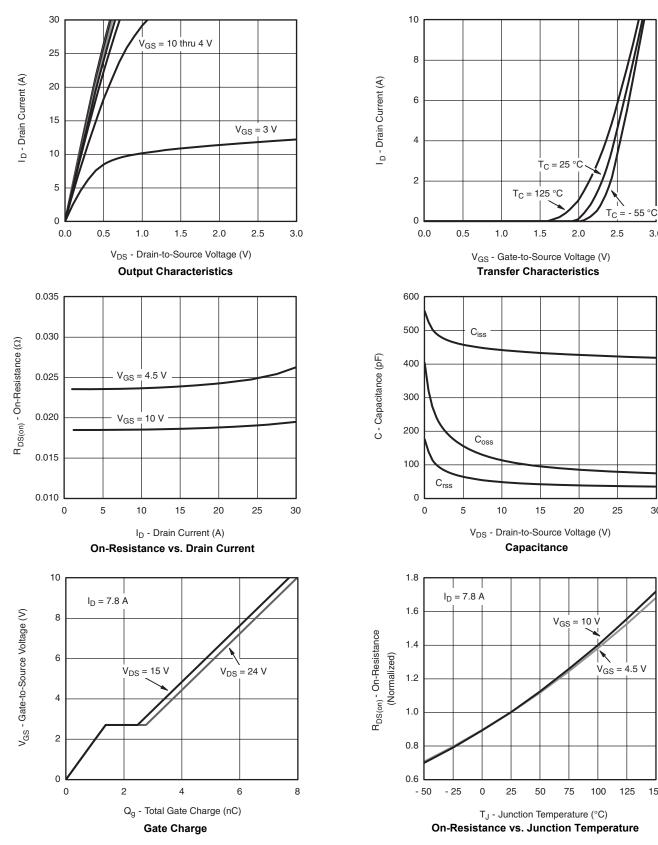
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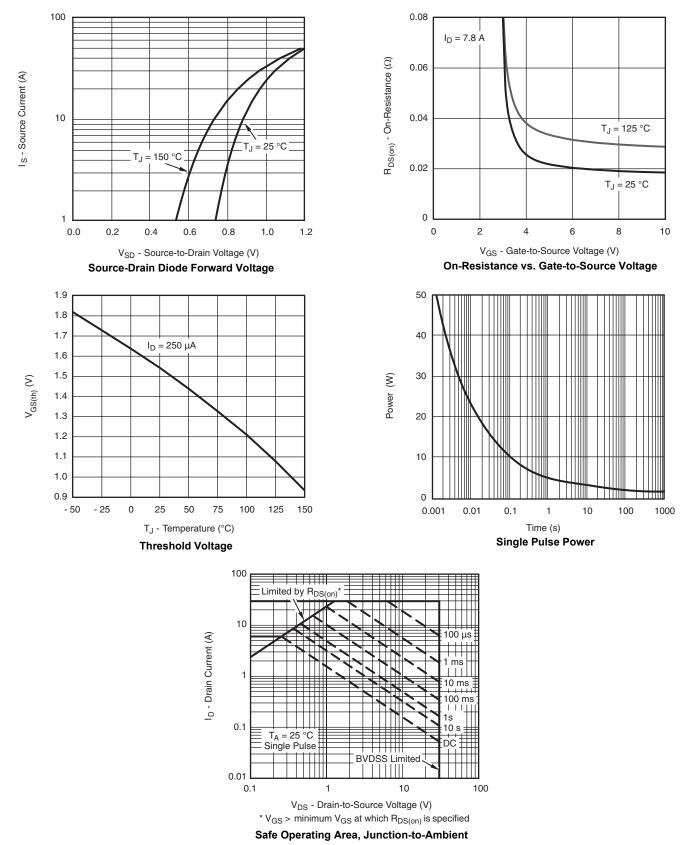
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



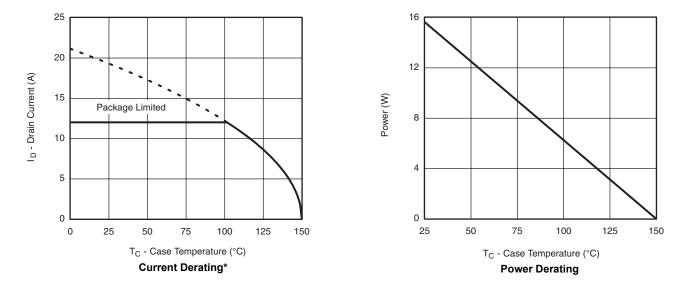
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

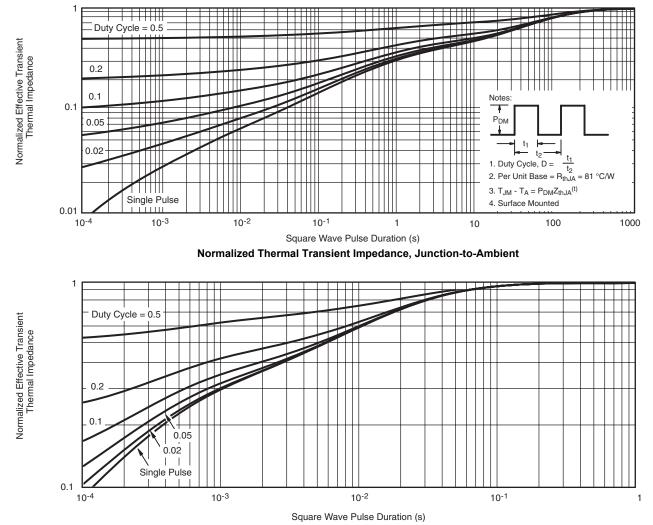




TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

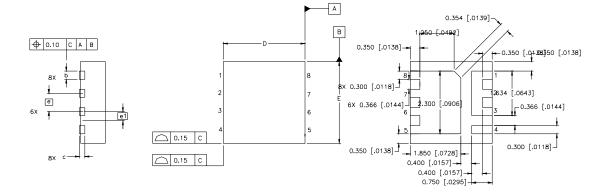
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Normalized Thermal Transient Impedance, Junction-to-Case

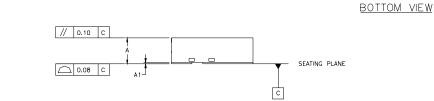


PQFN Package Details



<u>SIDE VIEW</u>

<u>top view</u>

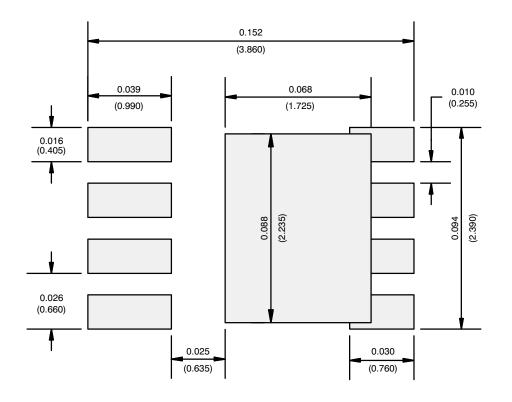


FRONT VIEW

DIM	INCH	IES	MILLIMETERS		
	MIN	MAX	MIN	MAX	
А	.0315	.0394	0.800	1.000	
A1	.0000	.0020	0.000	0.050	
b	.0098	.0138	0.250	0.350	
с	.0080	REF.	0.203 REF.		
D	.1181 BASIC		3.000 BASIC		
E	.1181	BASIC	3.000 BASIC		
е	.0262	BASIC	0.666	BASIC	
e1	.0131	BASIC	0.333	BASIC	



RECOMMENDED MINIMUM PADS



Recommended Minimum Pads Dimensions in Inches/(mm)



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